

新普科技股份有限公司  
新世電子(常熟)有限公司  
新普科技(重慶)有限公司  
兆普電子(上海)有限公司

Control Number : SLEU-1211006

## UN38.3 Test Report

### Recommendations on the TRANSPORT OF DANGEROUS GOODS


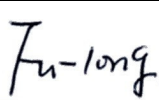

(Manual of Tests and Criteria, Fifth revised edition)

**Customer : Lenovo**

**Model : ASM P/N 45N1162**

**FRU P/N 45N1163**

**Rating : 10.8V , 4.4Ah / 48Wh**

Approved By	Checked By	Prepared By
		

SIMPLO TECHNOLOGY CO., LTD.

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## 1. Purpose of the Test :

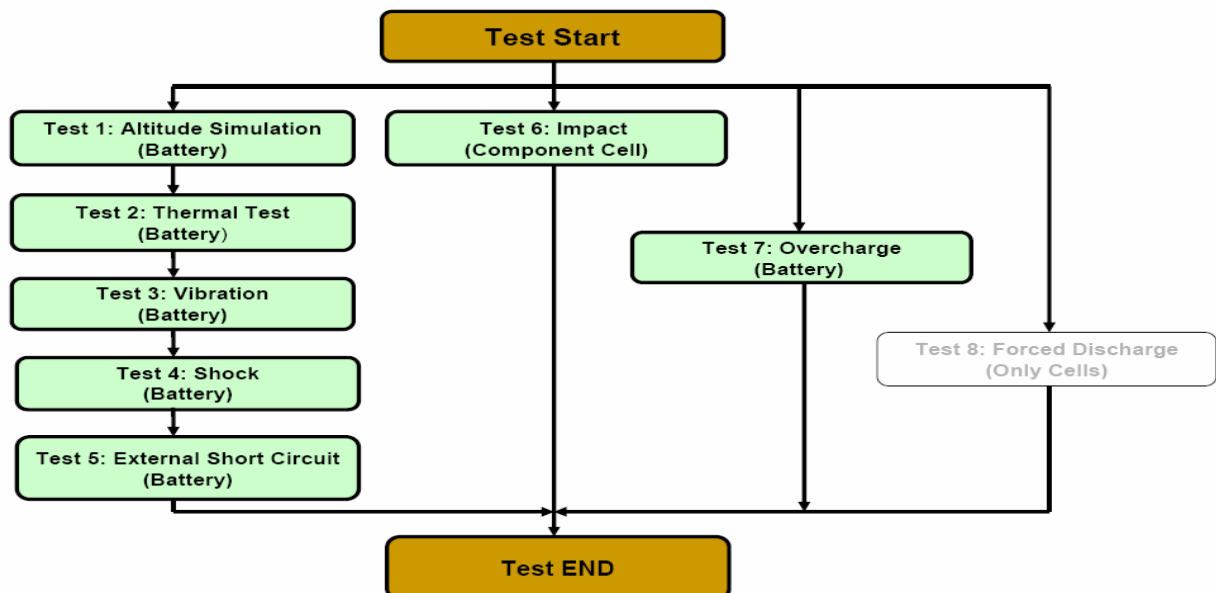
To test each cell/battery is of the type proved to meet the requirements in the Recommendations on the TRANSPORT OF DANGEROUS GOODS, Manual of Tests and Criteria, Fifth revised edition.

## 2. Test Quantity :

- 2.1 Four batteries, at first cycle, in fully charged states. (for T.1~T.5 test)
- 2.2 Four batteries, after fifty cycles ending in fully charged states. (for T.1~T.5 test)
- 2.3 Five component cells, at first cycle at 50% of the design rated capacity. (for T.6 test)
- 2.4 Four batteries, at first cycle, in fully charged states. (for T.7 test)
- 2.5 Four batteries, after fifty cycles ending in fully charged states. (for T.7 test)

## 3. Test Procedure :

- 3.1 All detail related test procedure shall be follow TRANSPORT OF DANGEROUS GOODS, Manual of Tests and Criteria, Fifth revised edition.
- 3.2 Test flow shall be follow below statement.





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#### 4. Test Result :

##### 4.1 T.1 ~T.4 Test results: **Pass**

4.1.1 All batteries could meet the requirement, mass loss less than 0.1% and voltage drop less than 10% after the test.

4.1.2 No leakage, no venting, no disassembly, no rupture and no fire.

##### 4.2 T.5 Test results: **Pass**

4.2.1 All batteries could meet the requirement, external temperature did not exceed 170°C.

4.2.2 All batteries were no disassembly, no rupture and no fire during the test and within six hours after the test.

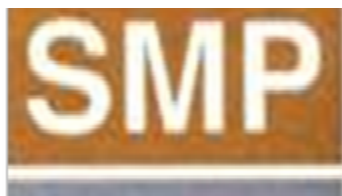
##### 4.3 T.6 Test results: **Pass**

4.3.1 All component cells could meet the requirement, external temperature did not exceed 170°C.

4.3.2 All component cells were no disassembly and no fire during the test and within six hours after the test.

##### 4.4 T.7 Test result: **Pass**

4.4.1 All batteries could meet no disassembly and no fire during the test and within seven days after the test.



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Control Number : SLEU-1211006

## 5. Test Equipment :

**SMP** SIMPLO TECHNOLOGY CO., LTD.

Revised date: 2012-11-21

Address : No. 471, Sec.2, Pa Teh Rd., Hu Kou, Hsin Chu Hsien 303 Taiwan

Date:2012-11-21

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Project No.: ASM P/N 45N1162 3S2P

FRU P/N 45N1163

Test Instruments Reference List

Used	Instrument ID	Instrument Name	Type	Range Used	Manufacturer	Calibration Date Last	Calibration Date Next	Remarks
	<b>Pretest</b>							
V	ML-761	Learning	715C	0~18V 0~8A	SMP	2012/5/25	2013/5/25	
V	ML-762	Learning	715C	0~18V 0~8A	SMP	2012/6/5	2013/6/5	
V	ML-763	Learning	715C	0~18V 0~8A	SMP	2012/6/13	2013/6/13	
	<b>T.1 Altitude Simulation</b>							
V	ML-522	Altitude		Kpa:30~90	新匠	2012/8/31	2013/8/31	
V	ML-257	Multimeter	HP 34401A	Note 1	Agilent	2012/7/6	2013/7/6	
V	ML-494	Electronic Balance	XS1220M-SCS	1-1000 gf	CHUANHUA	2012/8/31	2013/8/31	
V	ML-550	Data Logger	313	15~35 °C ; 30~80 %RH	CENTER	2012/10/19	2013/10/19	
	<b>T.2 Thermal Test</b>							
V	ML-018	Thermal Shock	WSF-602	T:-40 to 120°C	WIF	2012/1/31	2013/1/31	
V	ML-257	Multimeter	HP 34401A	Note 1	Agilent	2012/7/6	2013/7/6	
V	ML-494	Electronic Balance	XS1220M-SCS	1-1000 gf	CHUANHUA	2012/8/31	2013/8/31	
	<b>T.3 Vibration</b>							
V	ML-233	Vibration	KD-9636-EM-300F2K-30N80	F:5~2000Hz G:0.2~20G	King Design	2012/10/17	2013/10/17	
V	ML-257	Multimeter	HP 34401A	Note 1	Agilent	2012/7/6	2013/7/6	
V	ML-494	Electronic Balance	XS1220M-SCS	1-1000 gf	CHUANHUA	2012/8/31	2013/8/31	
V	ML-552	Data Logger	313	15~35 °C ; 30~80 %RH	CENTER	2012/10/19	2013/10/19	
	<b>T.4 Shock</b>							
V	ML-056	Shock	DP-1200-25	G:10~600G	King Design	2012/10/17	2013/10/17	
V	ML-257	Multimeter	HP 34401A	Note 1	Agilent	2012/7/6	2013/7/6	
V	ML-494	Electronic Balance	XS1220M-SCS	1-1000 gf	CHUANHUA	2012/8/31	2013/8/31	
V	ML-551	Data Logger	313	15~35 °C ; 30~80 %RH	CENTER	2012/10/19	2013/10/19	
	<b>T.5 External Short Circuit</b>							
V	ML-534	mΩ Hitester	3540	1mΩ ~ 30kΩ	YEOH LONG	2012/10/5	2013/10/5	
V	ML-339	Data Acquisition	MX100-E-1D	1-100 Vdc, -50 to 150°C	Yokogawa	2012/6/27	2013/6/27	
V	ML-521	Chamber	WIT IPC-1000(3F)	-20 to 150°C	WIT	2012/10/25	2013/10/25	
	<b>T.6 Impact ( Component cell )</b>							
V	ML-340	Data Acquisition	MX100-E-1D	1-100 Vdc, -50 to 150°C	Yokogawa	2012/4/26	2013/4/26	
V	ML-076	Impact Tester			JYI SHENG	2012/1/31	2013/1/31	
	<b>T.7 Overcharge</b>							
V	ML-481	Power Supply	DS10014	1-100Vdc, 0.3-14.4A	MOTECH	2012/6/27	2013/6/27	
V	ML-482	Power Supply	DS10014	1-100Vdc, 0.3-14.4A	MOTECH	2012/6/27	2013/6/27	
V	ML-483	Power Supply	DS10014	1-100Vdc, 0.3-14.4A	MOTECH	2012/6/27	2013/6/27	
V	ML-484	Power Supply	DS10014	1-100Vdc, 0.3-14.4A	MOTECH	2012/6/27	2013/6/27	
V	ML-485	Power Supply	DS10014	1-100Vdc, 0.3-14.4A	MOTECH	2012/6/27	2013/6/27	
V	ML-486	Power Supply	DS10014	1-100Vdc, 0.3-14.4A	MOTECH	2012/6/27	2013/6/27	
V	ML-487	Power Supply	DS6024	1-60 Vdc, 0.3-24A	MOTECH	2012/6/27	2013/6/27	
V	ML-488	Power Supply	DS6024	1-60 Vdc, 0.3-24A	MOTECH	2012/6/27	2013/6/27	
V	ML-489	Power Supply	DS6024	1-60 Vdc, 0.3-24A	MOTECH	2012/6/27	2013/6/27	
V	ML-490	Power Supply	DS6024	1-60 Vdc, 0.3-24A	MOTECH	2012/6/27	2013/6/27	
V	ML-549	Data Logger	313	15~35 °C ; 30~80 %RH	CENTER	2012/10/19	2013/10/19	

Note 1: DC Voltage: 0.1-1000V; AC Voltage: 0.5-700V at 60Hz, 1kHz; Resistance: 10Ω-10MΩ; DC Current: 0.1mA-3A; AC Current: 0.01-3A at 60Hz, 0.01-1A, at 1kHz.

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Control Number : SLEU-1211006

## 6. T.1~T.7 Detail Reports:

Control No.: SLEU-1211006

### UN 38.3 Test Datasheet

Customer: Lenovo

Model name: ASM P/N 45N1162 3S2P

Test duration: 2012/10/31~2012/11/21

Reviewer: Esmond

Test Sample Identification:

FRU P/N 45N1163

Used	Sample No.	Sample State	Used	Sample No.	Sample State	Used	Sample No.	Sample State
V	01~04	1 Cycle, Fully charged	V	05~08	50 Cycle, Fully charged			25Cycle, Fully charged
V	09~12	1 Cycle, Fully charged	V	13~16	50 Cycle, Fully charged			25Cycle, Fully charged
V	01C~05C	1 Cycle, 50% charged			1 Cycle, 50% charged			

#### T.1 Altitude Simulation

Start time: 11 / 12 / 08 : 34

Finish time: 11 / 12 / 15 : 11

Ambient temp.: 24.6 °C

Operator: Betty

Reviewer: Esmond

Sample No.: 01					Sample No.: 05						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.4	294.4	Mass loss %	0.00%	P	Mass (g)	294.3	294.2	Mass loss %	0.03%	P
OCV (V)	12.54	12.54	Remained OCV%	100.00%		OCV (V)	12.54	12.54	Remained OCV%	100.00%	
Sample No.: 02					Sample No.: 06						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.6	294.6	Mass loss %	0.00%	P	Mass (g)	294.3	294.3	Mass loss %	0.00%	P
OCV (V)	12.54	12.53	Remained OCV%	99.92%		OCV (V)	12.54	12.54	Remained OCV%	100.00%	
Sample No.: 03					Sample No.: 07						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.5	294.5	Mass loss %	0.00%	P	Mass (g)	294.5	294.5	Mass loss %	0.00%	P
OCV (V)	12.54	12.54	Remained OCV%	100.00%		OCV (V)	12.54	12.54	Remained OCV%	100.00%	
Sample No.: 04					Sample No.: 08						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.3	294.3	Mass loss %	0.00%	P	Mass (g)	294.6	294.6	Mass loss %	0.00%	P
OCV (V)	12.54	12.54	Remained OCV%	100.00%		OCV (V)	12.54	12.54	Remained OCV%	100.00%	

#### T.2 Thermal Test

Start time: 11 / 12 / 15 : 33

Finish time: 11 / 19 / 10 : 26

Ambient temp.: 24.1 °C

Operator: Betty

Reviewer: Esmond

Sample No.: 01					Sample No.: 05						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.4	294.3	Mass loss %	0.03%	P	Mass (g)	294.2	294.1	Mass loss %	0.03%	P
OCV (V)	12.54	12.40	Remained OCV%	98.88%		OCV (V)	12.54	12.39	Remained OCV%	98.80%	
Sample No.: 02					Sample No.: 06						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.6	294.6	Mass loss %	0.00%	P	Mass (g)	294.3	294.2	Mass loss %	0.03%	P
OCV (V)	12.53	12.40	Remained OCV%	98.96%		OCV (V)	12.54	12.38	Remained OCV%	98.72%	
Sample No.: 03					Sample No.: 07						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.5	294.4	Mass loss %	0.03%	P	Mass (g)	294.5	294.4	Mass loss %	0.03%	P
OCV (V)	12.54	12.39	Remained OCV%	98.80%		OCV (V)	12.54	12.41	Remained OCV%	98.96%	
Sample No.: 04					Sample No.: 08						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.3	294.3	Mass loss %	0.00%	P	Mass (g)	294.6	294.5	Mass loss %	0.03%	P
OCV (V)	12.54	12.39	Remained OCV%	98.80%		OCV (V)	12.54	12.39	Remained OCV%	98.80%	

#### T.3 Vibration

Start time: 11 / 19 / 10 : 51

Finish time: 11 / 20 / 11 : 56

Ambient temp.: 24.9 °C

Operator: Betty

Reviewer: Esmond

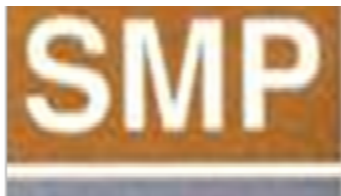
Sample No.: 01					Sample No.: 05						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.3	294.2	Mass loss %	0.03%	P	Mass (g)	294.1	294.1	Mass loss %	0.00%	P
OCV (V)	12.40	12.40	Remained OCV%	100.00%		OCV (V)	12.39	12.39	Remained OCV%	100.00%	
Sample No.: 02					Sample No.: 06						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.6	294.5	Mass loss %	0.03%	P	Mass (g)	294.2	294.1	Mass loss %	0.03%	P
OCV (V)	12.40	12.40	Remained OCV%	100.00%		OCV (V)	12.38	12.37	Remained OCV%	99.92%	
Sample No.: 03					Sample No.: 07						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.4	294.4	Mass loss %	0.00%	P	Mass (g)	294.4	294.3	Mass loss %	0.03%	P
OCV (V)	12.39	12.38	Remained OCV%	99.92%		OCV (V)	12.41	12.41	Remained OCV%	100.00%	
Sample No.: 04					Sample No.: 08						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.3	294.3	Mass loss %	0.00%	P	Mass (g)	294.5	294.5	Mass loss %	0.00%	P
OCV (V)	12.39	12.39	Remained OCV%	100.00%		OCV (V)	12.39	12.39	Remained OCV%	100.00%	

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Control Number : SLEU-1211006

T.4 Shock

Start time: 11 / 20 / 12 : 38  
Finish time: 11 / 20 / 14 : 53

Ambient temp.: 24.5 ℃

Operator: Betty

Reviewer: Esmond

Sample No.: 01					Sample No.: 05						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.2	294.2	Mass loss %	0.00%	P	Mass (g)	294.1	294.1	Mass loss %	0.00%	P
OCV (V)	12.40	12.40	Remained OCV%	100.00%		OCV (V)	12.39	12.38	Remained OCV%	99.92%	
Sample No.: 02					Sample No.: 06						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.5	294.5	Mass loss %	0.00%	P	Mass (g)	294.1	294.0	Mass loss %	0.03%	P
OCV (V)	12.40	12.40	Remained OCV%	100.00%		OCV (V)	12.37	12.37	Remained OCV%	100.00%	
Sample No.: 03					Sample No.: 07						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.4	294.3	Mass loss %	0.03%	P	Mass (g)	294.3	294.2	Mass loss %	0.03%	P
OCV (V)	12.38	12.38	Remained OCV%	100.00%		OCV (V)	12.41	12.41	Remained OCV%	100.00%	
Sample No.: 04					Sample No.: 08						
	Before	After	Variation		Results		Before	After	Variation		Results
Mass (g)	294.3	294.3	Mass loss %	0.00%	P	Mass (g)	294.5	294.4	Mass loss %	0.03%	P
OCV (V)	12.39	12.39	Remained OCV%	100.00%		OCV (V)	12.39	12.38	Remained OCV%	99.92%	

T.5 External Short Circuit

Start time: 11 / 20 / 15 : 26  
Finish time: 11 / 21 / 10 : 41

Ambient temp.: 23.6 ℃

Operator: Betty

Reviewer: Esmond

	Sample No.: 01		Sample No.: 02		Sample No.: 03		Sample No.: 04		Sample No.: 05		Sample No.: 06		Sample No.: 07		Sample No.: 08	
Resistance (<100mΩ)	52.3		53.7		57.8		59.6		54.9		56.6		57.5		54.2	
OCV before test/after short circuit(V)	12.40	0.01	12.40	0.00	12.38	0.00	12.39	0.00	12.38	0.00	12.37	0.00	12.41	0.00	12.38	0.01
Max Temp. (<170℃)	55.3		55.2		55.2		55.3		55.3		55.3		55.2		55.1	
Results	P		P		P		P		P		P		P		P	

T.6 Impact (Component cell)

Start time: 11 / 14 / 10 : 31  
Finish time: 11 / 15 / 14 : 24

Ambient temp.: 25.4 ℃

Operator: Betty

Reviewer: Esmond

	Sample No.: 01C	Sample No.: 02C	Sample No.: 03C	Sample No.: 04C	Sample No.: 05C
OCV before test(V)	3.59	3.60	3.60	3.59	3.60
Max Temp. (<170℃)	93.4	96.5	95.3	92.4	89.6
Results	P	P	P	P	P
	Sample No.: 06C	Sample No.: 07C	Sample No.: 08C	Sample No.: 09C	Sample No.: 10C
OCV before test(V)					
Max Temp. (<170℃)					
Results					

T.7 Overcharge

Start time: 11 / 13 / 08 : 46  
Finish time: 11 / 21 / 11 : 25

Ambient temp.: 24.4 ℃

Operator: Betty

Reviewer: Esmond

	Sample No.: 09	Sample No.: 10	Sample No.: 11	Sample No.: 12	Sample No.: 13	Sample No.: 14	Sample No.: 15	Sample No.: 16
OCV before test(V)	12.54	12.54	12.54	12.54	12.54	12.54	12.54	12.54
Results	P	P	P	P	P	P	P	P

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Control Number : SLEU-1211006

## 7. Equipment for Test:



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